

UltraChem® 100

Liquid Particle Counter

*Highly reliable particle counter
with 100 nm sensitivity for high
molecular scatter applications*

Without measurement there is no control



NanoVision Technology

Your products need reliable contamination monitoring. You need to detect the smallest particle possible. Now get both – sensitivity to 100 nm particles with the greatest reliability available on the market.

If your application requires measuring small particles in chemicals with high molecular scatter, UltraChem® 100 is the best tool for the job. NanoVision Technology® eliminates the competition between the light scattered by fluid molecules and particles. This makes 100 nm sizing possible for the first time.

Background and false counts are a thing of the past. The NanoVision Technology breakthrough ensures only information that matches a particle fingerprint is counted. The result: Data you can act on with confidence.



**PARTICLE
MEASURING
SYSTEMS®**

a spectris company



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BENEFITS

Detect Small Particles

- 100 nm sensitivity
- Large sample volume for improved data quality

NanoVision Technology®

- Adaptive technology makes the instrument immune to most optical contamination
- See what your particle counter sees
- Measures small particles in a wide range of chemicals, including high molecular scattering fluids. Chemicals include:
 - PGMEA
 - Photoresist solvents
 - HF
 - Sulfuric acid

Low Cost of Operation

- 2-year warrant
- Solid state laser diode
- Simple design

Versatile

- Online or batch sampling capabilities
- Multiple communication protocols
- Small footprint allows placement in various locations

APPLICATIONS

- DI water monitoring (cold and hot)
- Chemical distribution monitoring
- Chemical quality assurance
- Immersion lithography

UltraChem[®] 100

Liquid Particle Counter

Specifications

Size range	100 – 500 nm
Size channels	100, 200, 300, 500 nm
Flow rate	20 ml/min
Sample volume	6 ml/min nominal
Maximum concentration	3,000 particles/ml, Monitor mode 9,000 particles/ml, Spectrometer mode 15,000 particles /ml, High-Scatter mode
Sample temperature	50 – 302 °F (10 – 150 °C)
Zero count	< 20 counts/l
Maximum pressure	100 psi
Laser source	Laser diode Class I, complies with US 21 CFR 1040.10 and EN 60825-1; Internally an enclosed Class 4 laser is used per EN 60825-1
Wetted surface materials	Sapphire, Teflon [®] , Kel-F [®]
Dimensions (d, w, h)	17.5 x 13.75 x 9.1 in (44 x 35 x 23 cm)
Weight	35 lb (16 kg)
Power	100 – 240 VAC 1.25 Amp
Communications	Ethernet (PMS protocol) 4-20 mA RS-232 (for set up only)
Calibration	Materials used are traceable to National Institute of Standards and Technology (NIST) and/or Japanese Industrial Standards (JIS)
Environment	Temperature: 50 – 95 °F (10 – 35 °C); Humidity: Non-condensing Indoor use only Pollution degree 2 Over-voltages (transients) Category II Ordinary protection (not protected against harmful ingress of moisture) Class I equipment (Electrical earth ground from the mains power source to the product input is required for safety)
Warranty	2-year

HEADQUARTERS

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